

ISOM8110-EP Enhanced Product Single-Channel Opto-Emulator With Analog Transistor Output

1 Features

- Footprint compatible, pin-to-pin upgrade to industry-standard phototransistor optocouplers
- 1-channel LED-emulator input
- Current transfer ratio (CTR) at $I_F = 5\text{mA}$, $V_{CE} = 5\text{V}$: 100% to 155%
- High collector-emitter voltage: $V_{CE}(\text{max}) = 80\text{V}$
- Robust SiO_2 isolation barrier
 - Isolation rating: $3750\text{V}_{\text{RMS}}$
 - Working voltage: 500V_{RMS} , 707V_{PK}
 - Surge capability: 10kV_{PK}
- Extended temperature range: -55°C to 125°C
- Response time: $3\mu\text{s}$ (typical) at $V_{CE} = 10\text{V}$, $I_C = 2\text{mA}$, $R_L = 100\Omega$
- [Safety-Related Certifications](#) (Planned)
 - DIN EN IEC 60747-17 (VDE 0884-17)
 - UL 1577 recognition, $3750\text{V}_{\text{RMS}}$ and $5000\text{V}_{\text{RMS}}$ isolation
 - IEC 62368-1, IEC 61010-1 certifications
 - CQC GB 4943.1 certification

2 Applications

- [Aerospace and defense](#)
- [Switching power supply](#)
- [Avionics](#)
- [Sensors, imaging and radar](#)

3 Description

The ISOM8110-EP device is a single-channel optocoupler-emulator with LED-emulator input and transistor output. The device is footprint compatible and pin-to-pin upgrades for many traditional optocouplers, allowing enhancement to existing systems with no PCB redesign.

ISOM8110-EP opto-emulator offers significant reliability and performance advantages compared to optocouplers, including high bandwidth, low turn-off delay, low power consumption, wider temperature ranges, flat CTR, and tight process controls resulting in small part-to-part skew. Since there is no aging effect or temperature variation to compensate for, the emulated LED input stage consumes less power than optocouplers.

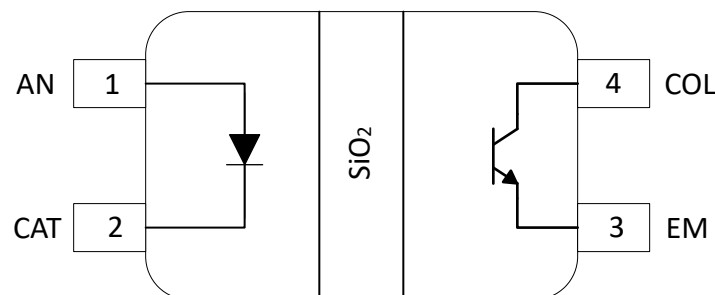
ISOM8110-EP is offered in a small SOIC-4 package with 2.54mm pin pitch, supporting a $3750\text{V}_{\text{RMS}}$ isolation rating. The high performance and reliability of ISOM8110-EP enables the device to be used in power supply feedback design, avionics, defense, and more.

Package Information

PART NUMBER	PACKAGE ⁽¹⁾	PACKAGE SIZE ⁽²⁾	BODY SIZE (NOM)
ISOM8110-EP	SO-4 (DFG)	7.0mm × 3.5mm	4.8mm × 3.5mm

(1) For more information, see [Section 11](#).

(2) The package size (length × width) is a nominal value and includes pins, where applicable.



Simplified Schematic

ADVANCE INFORMATION



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4 Pin Configuration and Functions

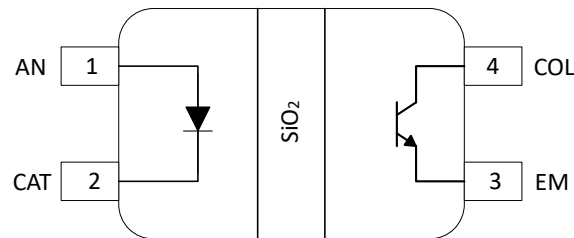


Figure 4-1. ISOM8110-EP 4-Pin SOIC (Top View)

Table 4-1. Pin Functions

PIN		TYPE ⁽¹⁾	DESCRIPTION
NO.	NAME		
1	AN	I	Anode connection of input LED emulator
2	CAT	I	Cathode connection of input LED emulator
3	EM	O	Emitter for transistor
4	COL	O	Collector for transistor

(1) I = Input, O = Output

5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range of -55°C to +125°C (unless otherwise noted) ⁽¹⁾ ⁽²⁾

		MIN	MAX	UNIT
$I_{F(max)}$	Maximum Input forward current		50	mA
V_{CEO}	Collector-emitter voltage		80	V
V_{ECO}	Emitter-collector voltage		7	V
I_{FP}	Input pulse forward current (1µs width)		1	A
V_R	Input reverse voltage		7	V
P_I	Input power dissipation		140	mW
I_C	Collector current		50	mA
P_C	Collector power dissipation		150	mW
P_T	Total power dissipation		290	mW
T_A	Ambient temperature	-55	125	°C
T_J	Junction temperature	-55	150	°C

- (1) Operation outside the Absolute Maximum Ratings may cause permanent device damage. Absolute Maximum Ratings do not imply functional operation of the device at these or any other conditions beyond those listed under the operational sections of this document. If used outside the listed operational conditions but within the Absolute Maximum Ratings, the device may not be fully functional, and this may affect device reliability, functionality, performance, and shorten the device lifetime.
- (2) All specifications are at $T_A = 25^\circ\text{C}$ unless otherwise noted

5.2 ESD Ratings

			VALUE	UNIT
$V_{(ESD)}$	Electrostatic discharge	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins ⁽¹⁾	±2000	V
		Charged device model (CDM), per JEDEC specification JESD22-C101, all pins ⁽²⁾	±1000	

- (1) JEDEC document JEP155 states that 500V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250V CDM allows safe manufacturing with a standard ESD control process.

5.3 Recommended Operating Conditions

over operating free-air temperature range of -55°C to +125°C (unless otherwise noted)

		MIN	NOM	MAX	UNIT
$I_{F(ON)}$	Input ON-state forward current	0.7		20	mA
V_R	Input reverse voltage			5	V
V_{CEO}	Collector-emitter voltage	-5		48	V
T_A	Ambient temperature	-55		125	°C

5.4 Thermal Information

THERMAL METRIC ⁽¹⁾		ISOM8110-EP	UNIT
		DFG (SOIC)	
		4 PINS	
R _{θJA}	Junction-to-ambient thermal resistance	283.9	°C/W
R _{θJC(top)}	Junction-to-case (top) thermal resistance	173.1	°C/W
R _{θJB}	Junction-to-board thermal resistance	201.4	°C/W
Ψ _{JT}	Junction-to-top characterization parameter	125.1	°C/W
Ψ _{JB}	Junction-to-board characterization parameter	198.0	°C/W

(1) For more information about traditional and new thermal metrics, see [Semiconductor and IC Package Thermal Metrics](#) application note.

5.5 Insulation Specifications

PARAMETER		TEST CONDITIONS	VALUE	UNIT
			4-DFG	
IEC 60664-1				
CLR	External clearance ⁽¹⁾	Side 1 to side 2 distance through air	> 5	mm
CPG	External creepage ⁽¹⁾	Side 1 to side 2 distance across package surface	> 5	mm
DTI	Distance through the insulation	Minimum internal gap (internal clearance)	>17	μm
CTI	Comparative tracking index	IEC 60112; UL 746A	>400	V
	Material Group	According to IEC 60664-1	II	
	Overvoltage category per IEC 60664-1	Rated mains voltage ≤ 150 V _{RMS}	I-IV	
		Rated mains voltage ≤ 300 V _{RMS}	I-IV	
		Rated mains voltage ≤ 600 V _{RMS}	I-III	
DIN VDE V 0884-11:2017 ⁽⁶⁾				
V _{IORM}	Maximum repetitive peak isolation voltage	AC voltage (bipolar)	707	V _{PK}
V _{IOWM}	Maximum isolation working voltage	AC voltage (sine wave); time-dependent dielectric breakdown (TDDb) test	500	V _{RMS}
		DC voltage	707	V _{DC}
V _{IOTM}	Maximum transient isolation voltage	V _{TEST} = V _{IOTM} , t = 60s (qualification); V _{TEST} = 1.2 × V _{IOTM} , t = 1s (100% production)	5303	V _{PK}
V _{IMP}	Maximum impulse voltage ⁽²⁾	Tested in air, 1.2/50μs waveform per IEC 62368-1	7200	V _{PK}
V _{IOSM}	Maximum surge isolation voltage ⁽³⁾	V _{IOSM} ≥ 1.3 × V _{IMP} ; tested in oil (qualification test), 1.2/50μs waveform per IEC 62368-1	10000	V _{PK}
q _{pd}	Apparent charge ⁽⁴⁾	Method a: After I/O safety test subgroup 2/3, V _{ini} = V _{IOTM} , t _{ini} = 60s; V _{pd(m)} = 1.2 × V _{IORM} , t _m = 10s	≤ 5	pC
		Method a: After environmental tests subgroup 1, V _{ini} = V _{IOTM} , t _{ini} = 60s; V _{pd(m)} = 1.6 × V _{IORM} , t _m = 10s	≤ 5	
		Method b: At routine test (100% production) and preconditioning (type test), V _{ini} = 1.2 × V _{IOTM} , t _{ini} = 1s; V _{pd(m)} = 1.875 × V _{IORM} , t _m = 1s	≤ 5	
C _{IO}	Barrier capacitance, input to output ⁽⁵⁾	V _{IO} = 0.4 × sin (2 πft), f = 1MHz	1	pF
R _{IO}	Insulation resistance, input to output ⁽⁵⁾	V _{IO} = 500V, T _A = 25°C	> 10 ¹²	Ω
		V _{IO} = 500V, 100°C ≤ T _A ≤ 125°C	> 10 ¹¹	
		V _{IO} = 500V at T _S = 150°C	> 10 ⁹	
	Pollution degree		2	
	Climatic category		40/125/21	
UL 1577				
V _{ISO}	Withstand isolation voltage	V _{TEST} = V _{ISO} , t = 60s (qualification); V _{TEST} = 1.2 × V _{ISO} , t = 1s (100% production)	3750	V _{RMS}

- (1) Creepage and clearance requirements should be applied according to the specific equipment isolation standards of an application. Care should be taken to maintain the creepage and clearance distance of a board design to ensure that the mounting pads of the isolator on the printed-circuit board do not reduce this distance. Creepage and clearance on a printed-circuit board become equal in certain cases. Techniques such as inserting grooves, ribs, or both on a printed circuit board are used to help increase these specifications.
- (2) Testing is carried out in air to determine the surge immunity of the package.
- (3) Testing is carried out in oil to determine the intrinsic surge immunity of the isolation barrier.
- (4) Apparent charge is electrical discharge caused by a partial discharge (pd).
- (5) All pins on each side of the barrier tied together creating a two-pin device.
- (6) This coupler is suitable for *safe electrical insulation only* within the safety ratings. Compliance with the safety ratings shall be ensured by means of suitable protective circuits.

5.6 Safety-Related Certifications

VDE	UL
Plan to certify according to DIN EN IEC 60747-17 (VDE 0884-17)	Plan to certify according to UL 1577 Component Recognition Program
Certificate planned	Certificate planned

5.7 Safety Limiting Values

Safety limiting⁽¹⁾ intends to minimize potential damage to the isolation barrier upon failure of input or output circuitry.

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
SO-4 PACKAGE (DFG)					
I _S	Safety limiting input current	R _{θJA} = 283.9°C/W, V _F = 1.4V, T _J = 150°C, T _A = 25°C		300	mA
		R _{θJA} = 283.9°C/W, V _{CEO} = 30V, T _J = 150°C, T _A = 25°C		13.5	mA
		R _{θJA} = 283.9°C/W, V _{CEO} = 24V, T _J = 150°C, T _A = 25°C		17.5	mA
		R _{θJA} = 283.9°C/W, V _{CEO} = 15V, T _J = 150°C, T _A = 25°C		28	mA
P _S	Safety limiting total power	R _{θJA} = 283.9°C/W, T _J = 150°C, T _A = 25°C		420	mW
T _S	Maximum safety temperature			150	°C

- (1) The I_S and P_S parameters represent the safety current and safety power respectively. The maximum limits of I_S and P_S must not be exceeded. These limits vary with the ambient temperature, T_A.
The junction-to-air thermal resistance, R_{θJA}, in the table is that of a device installed on a high-K test board for leaded surface-mount packages. Use these equations to calculate the value for each parameter:
T_J = T_A + R_{θJA} × P, where P is the power dissipated in the device.
T_{J(max)} = T_S = T_A + R_{θJA} × P_S, where T_{J(max)} is the maximum allowed junction temperature.
P_S = I_S × V_I, where V_I is the maximum input voltage.

5.8 Electrical Characteristics

over recommended operating conditions unless otherwise noted

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
INPUT						
V_F	Input forward voltage	$I_F = 5\text{mA}$		1.2	1.6	V
I_R	Input reverse current	$V_R = 5\text{V}$			10	μA
C_{IN}	Input capacitance	At 1MHz, $V_F = 0\text{V}$, $T_A = 25^\circ\text{C}$		20		pF
OUTPUT						
C_{CE}	Collector-emitter capacitance	1MHz, $V_F = 0\text{V}$, $T_A = 25^\circ\text{C}$		15		pF
$V_{CE(SAT)}$	Collector-emitter saturation voltage	$I_F = 10\text{mA}$, $I_C = 1\text{mA}$			0.3	V
I_{C_DARK}	Collector dark current	$V_{CE} = 20\text{V}$, $I_F = 0\text{mA}$			100	nA
I_{EC}	Reverse current	$V_{EC} = 5\text{V}$, $I_F = 0\text{mA}$			50	μA
I_{C_OFF}	OFF_state collector current	$V_F = 0.7\text{V}$, $V_{CE} = 30\text{V}$			10	μA
CTR ⁽¹⁾	Current Transfer Ratio	$I_F = 2\text{mA}$, $V_{CE} = 5\text{V}$	80	130	180	%
		$I_F = 5\text{mA}$, $V_{CE} = 5\text{V}$	100	120	155	%

(1) $CTR (\%) = (I_C / I_F) \times 100\%$

5.9 Switching Characteristics

All specifications are at $T_A = 25^\circ\text{C}$ unless otherwise noted

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
AC						
t_r	Rise time, see Figure 6-2 and Figure 6-3	$V_{CC} = 10\text{V}$, $I_C = 2\text{mA}$, $R_L = 100\Omega$, $C_L = 50\text{pF}$		3.2		μs
t_f	Fall time, see Figure 6-2 and Figure 6-3	$V_{CC} = 10\text{V}$, $I_C = 2\text{mA}$, $R_L = 100\Omega$, $C_L = 50\text{pF}$		4.0		μs
T_{ON}	Turn on time, see Figure 6-2 and Figure 6-3	$V_{CC} = 10\text{V}$, $I_C = 2\text{mA}$, $R_L = 100\Omega$, $C_L = 50\text{pF}$		5.7		μs
		$V_{CC}=5\text{V}$, $R_L=4.7\text{k}\Omega$, $I_F=1.6\text{mA}$, $C_L=50\text{pF}$		3.5		μs
		$V_{CC}=5\text{V}$, $R_L=1.9\text{k}\Omega$, $I_F=16\text{mA}$, $C_L=50\text{pF}$		0.62		μs
T_{OFF}	Turn off time, see Figure 6-2 and Figure 6-3	$V_{CC} = 10\text{V}$, $I_C = 2\text{mA}$, $R_L = 100\Omega$, $C_L = 50\text{pF}$		3.6		μs
		$V_{CC}=5\text{V}$, $R_L=4.7\text{k}\Omega$, $I_F=1.6\text{mA}$, $C_L=50\text{pF}$		8		μs
		$V_{CC}=5\text{V}$, $R_L=1.9\text{k}\Omega$, $I_F=16\text{mA}$, $C_L=50\text{pF}$		10		μs
t_s	Storage time; time required for the output waveform to change from 0% (100%) to 10% (90%) when input is turned on and back off, see Figure 6-2 and Figure 6-3	$V_{CC} = 5\text{V}$, $I_F = 1.6\text{mA}$, $R_L = 4.7\text{k}\Omega$			21	μs
BW	Bandwidth, see Figure 6-4	$V_{IN_DC} = 5\text{V}$, $V_{IN_AC} = 1\text{Vpk}$, $R_{IN} = 2\text{k}\Omega$, $V_{CC} = 5\text{V}$, $R_{LOAD} = 100\Omega$, $C_L = 50\text{pF}$, measured at $V_{CE} -3\text{dB}$ sinewave		680		kHz

6 Parameter Measurement Information

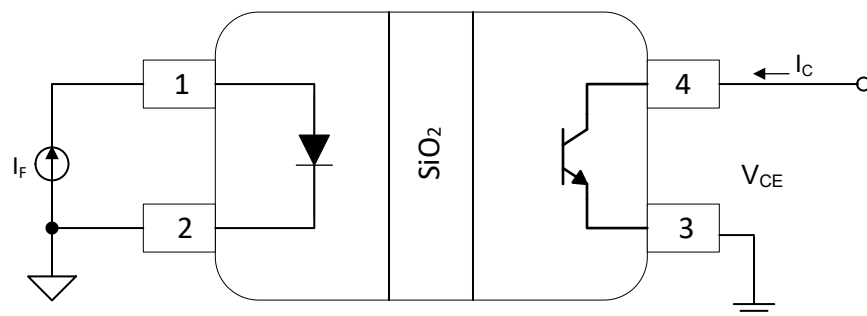


Figure 6-1. ISOM8110-EP Test Circuit for CTR

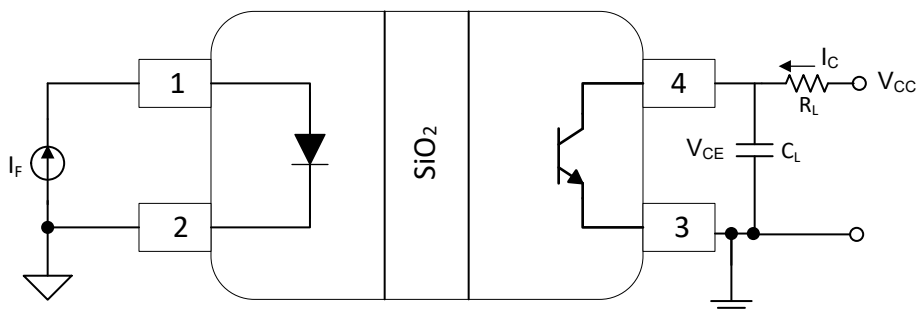


Figure 6-2. ISOM8110-EP Test Circuit for Switching Timing

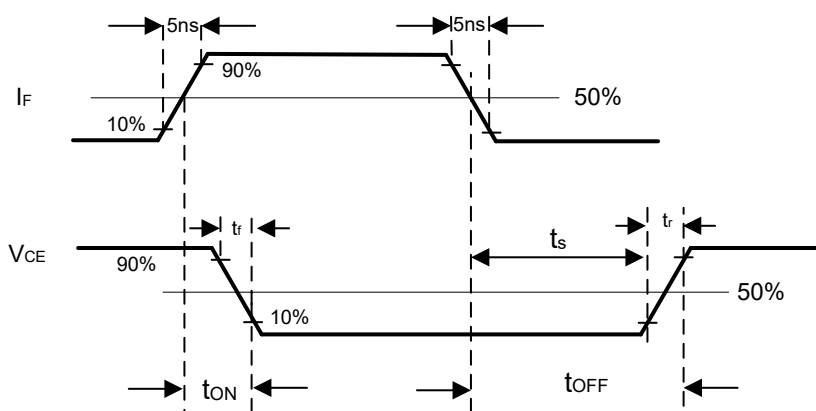


Figure 6-3. ISOM8110-EP Switching Timing Waveforms

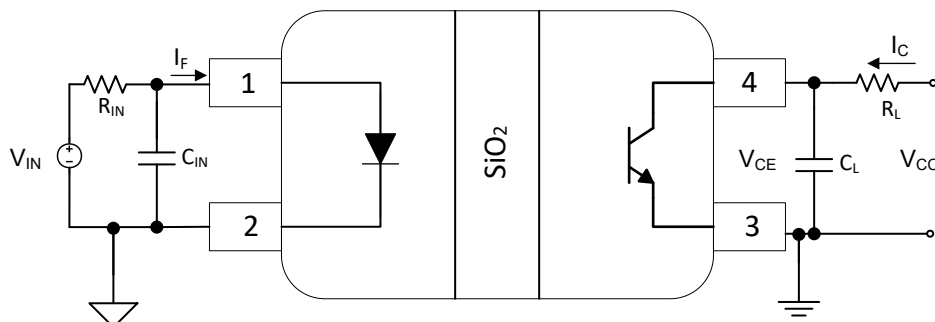


Figure 6-4. ISOM8110-EP Test Circuit for Bandwidth

7 Detailed Description

7.1 Overview

The ISOM8110-EP opto-emulator is a single-channel, pin-to-pin upgrade for many traditional optocouplers. While standard optocouplers use an LED as the input stage, ISOM8110-EP uses an emulated LED as the input stage. The input and output stages are isolated by TI's proprietary silicon dioxide-based (SiO_2) isolation barrier. This isolation technology makes ISOM8110-EP resistant to the wear-out effects found in optocouplers that degrade performance with increasing temperature, forward current, and device age. Ordering options include four different ranges of current transfer ratio (CTR).

The functional block diagram of ISOM8110-EP is shown in [Section 7.2](#). The input signal is transmitted across the isolation barrier using an on-off keying (OOK) modulation scheme. The transmitter sends a high-frequency carrier across the barrier that contains information on how much current is flowing through the input pins. The receiver demodulates the signal after advanced signal conditioning and produces the signal through the output stage. This device also incorporates advanced circuit techniques to maximize bandwidth and minimize radiated emissions. [Figure 7-2](#) shows conceptual details of how the OOK scheme works.

7.2 Functional Block Diagram

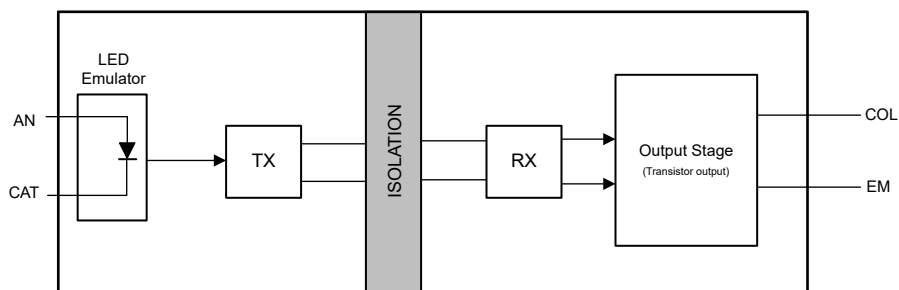


Figure 7-1. Conceptual Block Diagram of an Opto-emulator ISOM8110-EP

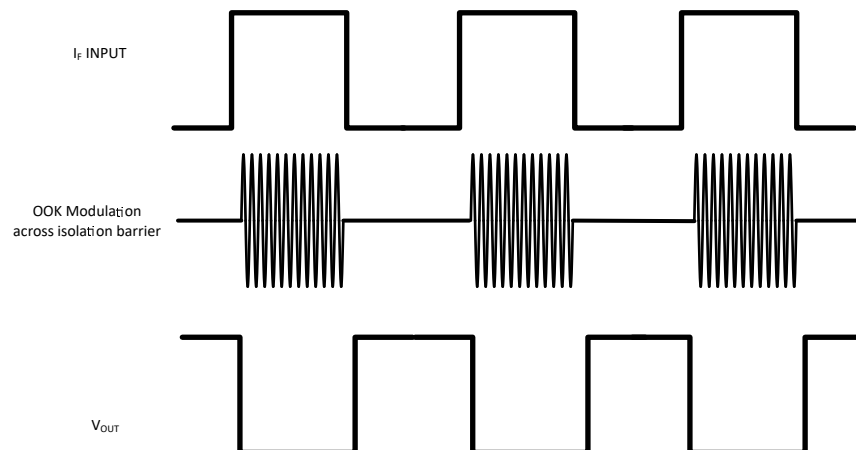


Figure 7-2. On-off Keying (OOK) Based Modulation Scheme

7.3 Feature Description

The ISOM8110-EP device can isolate both analog and digital signals due to the current-driven input stage. When supplied an input current (I_F) of at least 0.7mA to the AN pin. This powers the internal modulator which includes the modulator and current sense blocks. The I_F is sensed and converted into a high frequency carrier that is passed across the isolation barrier. Once demodulated on the secondary side of the device, this is used to bias the output transistor which tries to sink current from an external source into the COL pin (I_C) proportional to the I_F value. The ratio of I_C to I_F is the current transfer ratio (CTR).

7.4 Device Functional Modes

7.4.1 Active Mode

If the external source or circuit connected to the COL pin can supply enough current to satisfy the CTR of the device for a given I_F value, then the device is considered in "active mode". This is how analog signals can be transmitted through this device.

7.4.2 Saturation Mode

If the external source or circuit connected to the COL pin cannot supply enough current to satisfy the CTR of the device for a given I_F value (For example, $I_C = 1\text{mA}$ when $I_F = 10\text{mA}$), then the output transistor saturates and goes into a low impedance state. The device is considered in "saturation mode". This is how digital signals can be transmitted through this device.

8 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

8.1 Application Information

ISOM8110-EP is commonly used in the feedback control loops of isolated power supplies. This device is used to solve the problem of feeding back current while isolating the primary and secondary domains to regulate the output voltage.

In power supplies, the output voltage is isolated from main input voltage using a transformer (for example: flyback converter). For analog power supply units, the controller IC is typically on the primary side of the transformer. For closed loop control, measuring the output voltage on the secondary side and feeding the voltage back to the controller on the primary is necessary. The most common method of achieving this design is using an isolator such as ISOM8110-EP, error amplifier (commonly TL1431-EP), and a voltage comparator to form a feedback loop across the isolation barrier.

Figure 8-1 illustrates a typical isolated power supply. In this implementation, the output voltage is sensed by an error amplifier using the resistor divider (R1 and R2). Depending on the voltage level that the error amplifier senses, the TL1431-EP can drive the current of the ISOM8110-EP higher or lower which is then compared to a voltage reference. The information is passed across the isolation barrier through ISOM8110-EP to the primary side, where the PWM control circuit modulates the power stage to regulate the output voltage. The TL1431-EP and ISOM8110-EP play an important role for stable feedback and control loop.

The ISOM8110-EP devices enable improvements in transient response, reliability, and stability as compared to commonly used optocoupler as the CTR is stable over wide temperature range providing a small, low-cost, highly reliable, and easy-to-design implementation.

8.1.1.2.1 Sizing R_{PULLUP}

The transistor output of ISOM8110-EP operates in active, saturation, reverse, and cut-off regions, just like a regular transistor. To verify that the output does not get damaged when the output is saturated, the minimum value of R_{PULLUP} can be calculated for a given pull-up voltage, V_{PULLUP} , in Equation 1:

$$R_{PULLUP} > \frac{V_{PULLUP} - V_{CE(SAT)}}{I_{C(MAX)}} \quad (1)$$

For the example of a feedback loop application, we can calculate the minimum required value for R_{PULLUP} for a given V_{PULLUP} of 10V, the maximum output voltage of the error amplifier ($V_{COMP(MAX)}$) of 2.5V, and the maximum output current of the error amplifier is internally clamped at 1.6mA. The equation to calculate R_{PULLUP} is shown in Equation 2:

$$R_{PULLUP} > \frac{V_{PULLUP} - V_{COMP(MAX)}}{I_{COMP(CLAMP)}} = \frac{10V - 2.5V}{1.6mA} = 4.66k\Omega \quad (2)$$

8.1.1.2.2 Sizing R_{IN}

The input side of ISOM8110-EP is current-driven. To limit the amount of current flowing into the AN pin, placing a series resistor, R_{IN} , in series with the input as shown in Figure 8-1 is recommended.

Depending on how the ISOM8110-EP device is being used, the value of R_{IN} can vary quite a bit. However, at a high level, to make sure the input does not get damaged, the minimum value of R_{IN} can be calculated for a given input voltage, V_{IN} , in Equation 3:

$$R_{IN} > \frac{V_{IN} - V_F}{I_{C(MAX)}} \quad (3)$$

However, in the use case of a feedback loop, R_{IN} directly affects the mid-band gain of the loop. Assuming that the TL431 has been configured to give a reference voltage, V_{REF} , of 2.5V and R_{PULLUP} is 5k Ω , Equation 4 is used to calculate the maximum value of R_{IN} verifying that the V_{COMP} voltage on the primary side can be pulled to the saturation voltage of the ISOM8110-EP, $V_{CE(SAT)}$.

$$R_{IN} < \frac{(V_{OUT} - V_{REF} - V_F) \times R_{PULLUP} \times CTR_{MIN}}{V_{PULLUP} - V_{CE(SAT)}} = \frac{(5V - 2.5V - 1.2V) \times 5k\Omega \times 100\%}{10V - 0.3V} = 670\Omega \quad (4)$$

8.1.1.3 Application Curves

The following curves show ISOM8110-EP bandwidth performance over different loading conditions where $V_{IN} = 5V_{DC} + 2V_{PK}$. See Figure 6-4 for setup details.

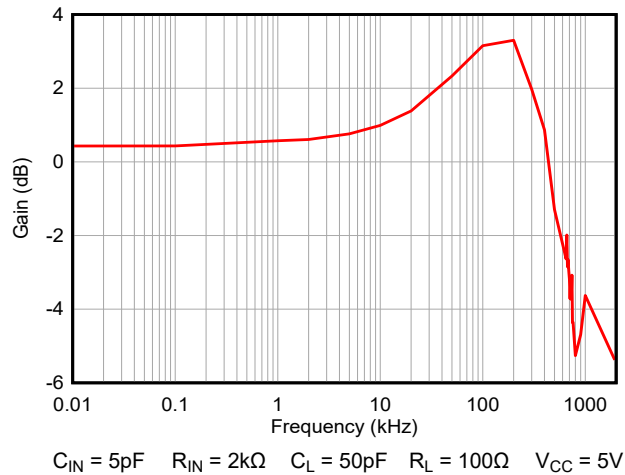


Figure 8-2. Bandwidth at $R_L = 100\Omega$

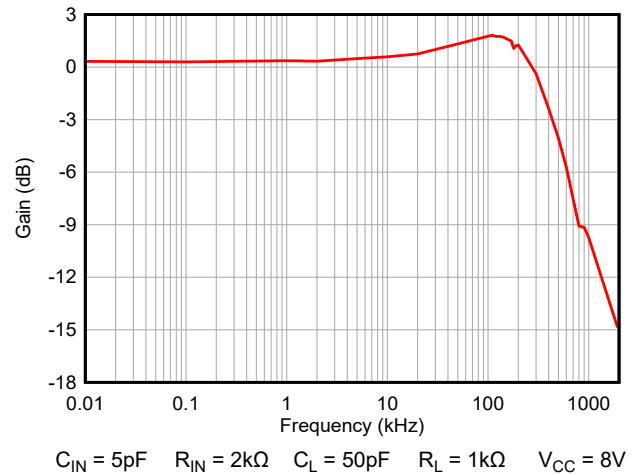


Figure 8-3. Bandwidth at $R_L = 1\text{k}\Omega$

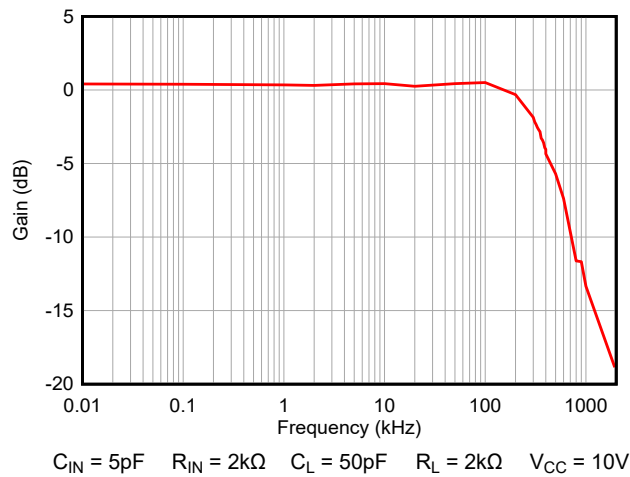


Figure 8-4. Bandwidth at $R_L = 2\text{k}\Omega$

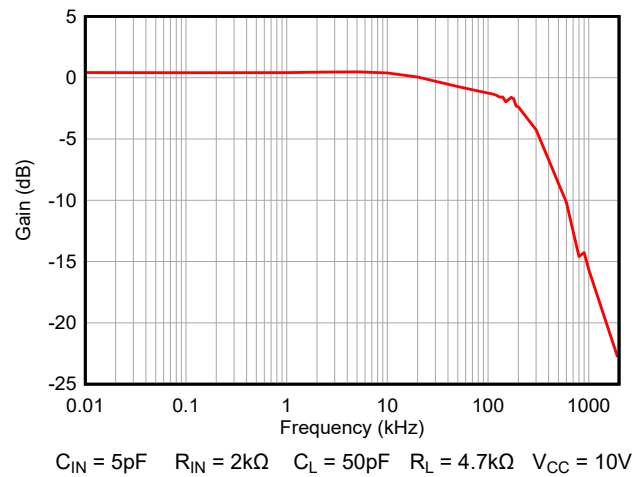


Figure 8-5. Bandwidth at $R_L = 4.7\text{k}\Omega$

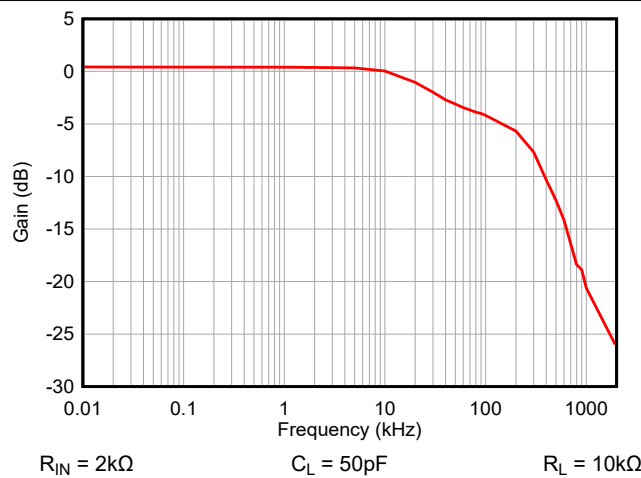


Figure 8-6. Bandwidth at $R_L = 10\text{k}\Omega$

8.2 Power Supply Recommendations

ISOM8110-EP does not require a dedicated power supply to operate since there is no supply pin. Take care to not violate recommended I/O specifications for proper device functionality.

8.3 Layout

8.3.1 Layout Guidelines

- The device connections to ground must be tied to the PCB ground plane using a direct connection or two vias to help minimize inductance.
- The connections of capacitors and other components to the PCB ground plane must use a direct connection or two vias for minimum inductance.

8.3.2 Layout Example

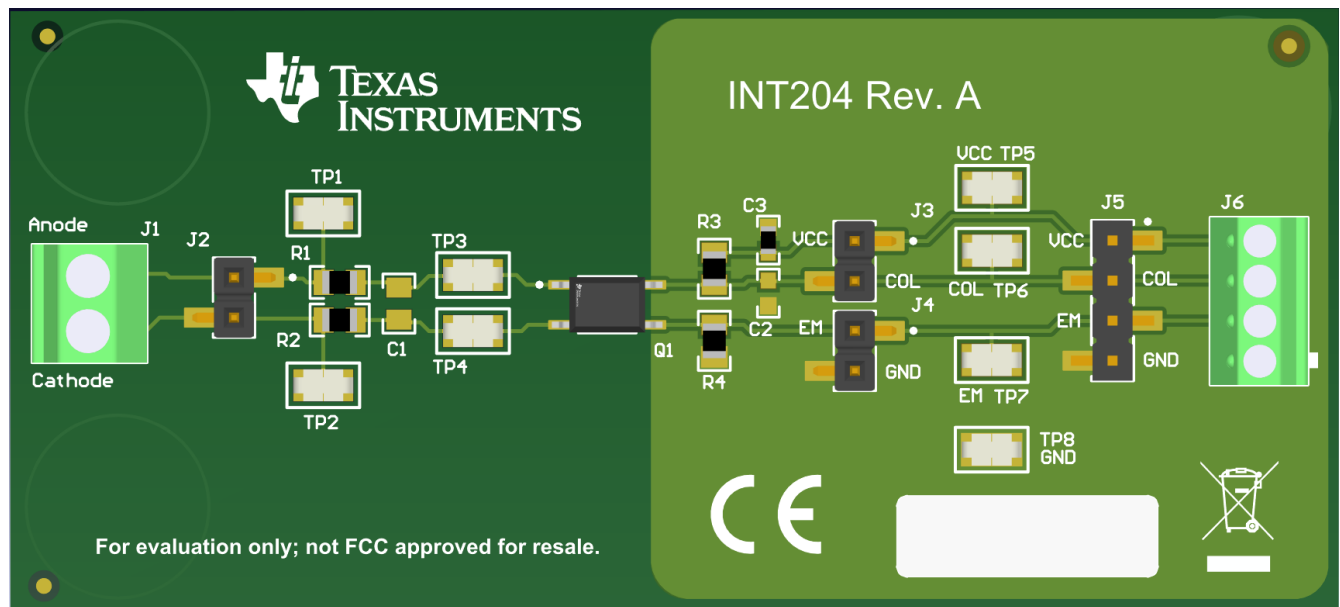


Figure 8-7. Layout Example of ISOM8110-EP With a Single Layer Board

9 Device and Documentation Support

9.1 Documentation Support

9.1.1 Related Documentation

For related documentation see the following:

- Texas Instruments, [Isolation Glossary](#), application note
- Texas Instruments, [Introduction to Opto-Emulators](#), application note
- Texas Instruments, [ISOM8110 Single-Channel Opto-Emulator with Analog Transistor Output Evaluation Module](#), EVM user's guide

9.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on [ti.com](#). Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

9.3 Support Resources

[TI E2E™ support forums](#) are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's [Terms of Use](#).

9.4 Trademarks

TI E2E™ is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

9.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

9.6 Glossary

[TI Glossary](#) This glossary lists and explains terms, acronyms, and definitions.

10 Revision History

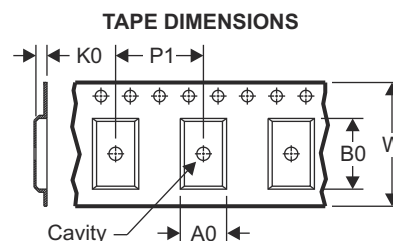
NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

DATE	REVISION	NOTES
August 2025	*	Initial Release

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical packaging and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

ADVANCE INFORMATION

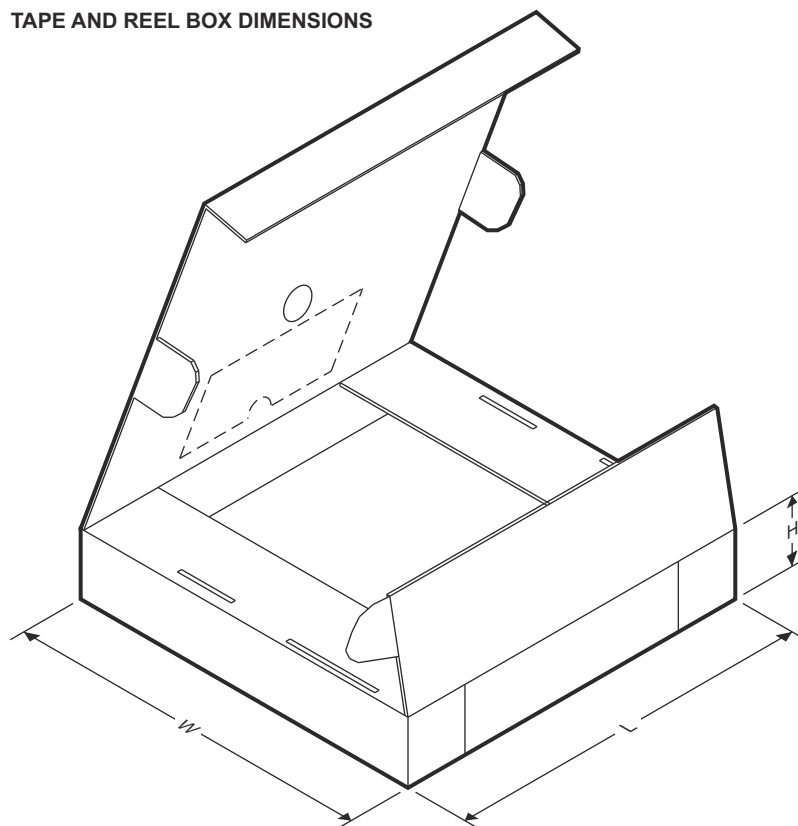


A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

A schematic diagram of a multi-pocket cassette tape. The tape is represented as a horizontal strip with a series of sprocket holes along its top edge. The tape is divided into three pockets. The first two pockets are labeled with quadrant numbers: Q1 (top-left), Q2 (top-right), Q3 (bottom-left), and Q4 (bottom-right). A third, smaller pocket is shown on the right. A large arrow points to the right, labeled "User Direction of Feed". Labels "Sprocket Holes" and "Pocket Quadrants" point to their respective features.

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
XISOM8110DFGTEP	SO-4	DFG	4	250	330.0	12.4	8.0	3.8	2.7	12.0	12.0	Q1

TAPE AND REEL BOX DIMENSIONS



Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
XISOM8110DFGTEP	SO-4	DFG	4	250	356.0	356.0	35.0

ADVANCE INFORMATION

PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
XISOM8110DFGTEP	Active	Preproduction	SOIC (DFG) 4	250 SMALL T&R	-	Call TI	Call TI	-55 to 125	

(1) **Status:** For more details on status, see our [product life cycle](#).

(2) **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

(3) **RoHS values:** Yes, No, RoHS Exempt. See the [TI RoHS Statement](#) for additional information and value definition.

(4) **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

(5) **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

(6) **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF ISOM8110-EP :

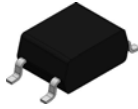
● Catalog : [ISOM8110](#)

● Automotive : [ISOM8110-Q1](#)

NOTE: Qualified Version Definitions:

- Catalog - TI's standard catalog product
- Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

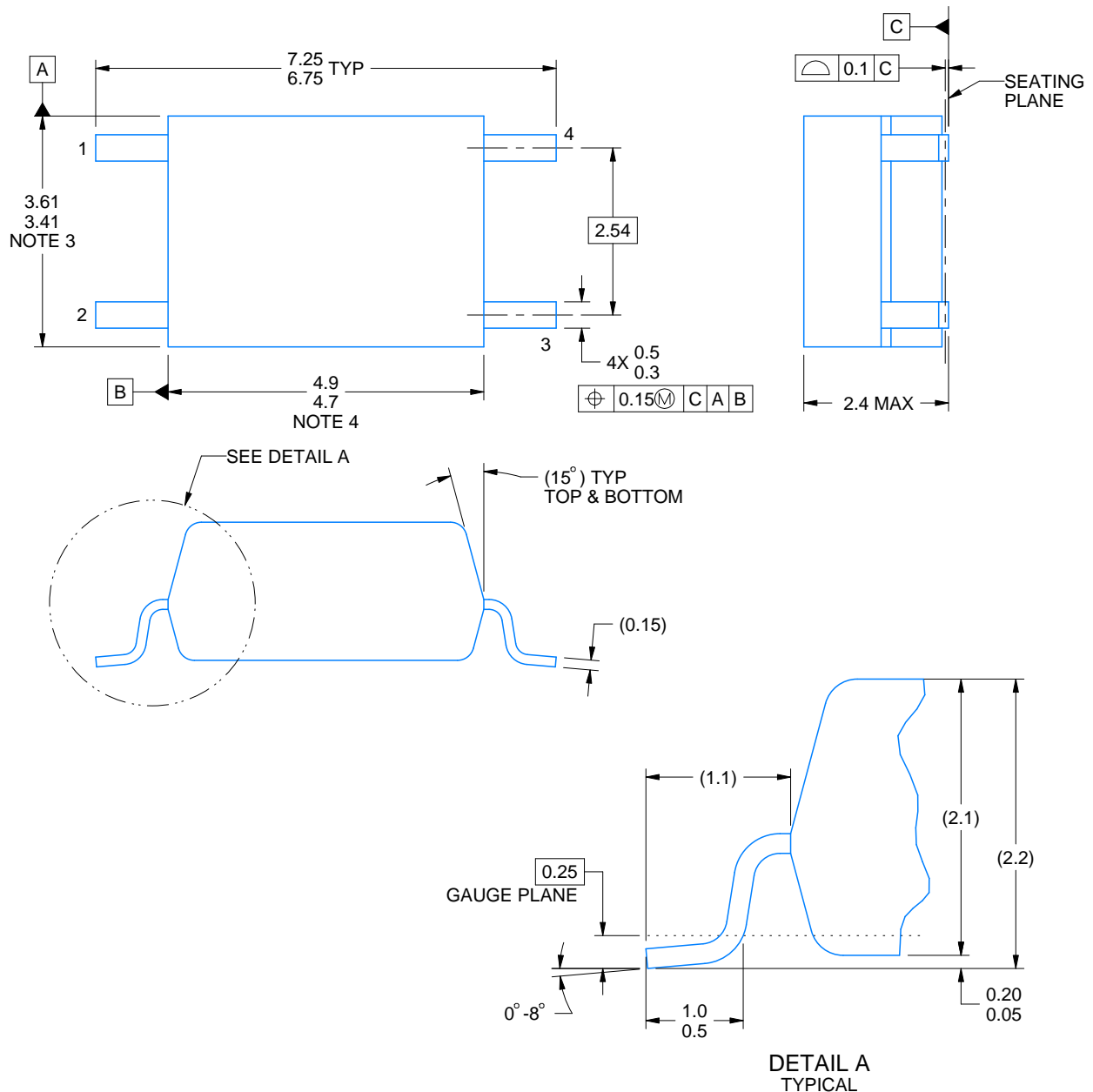
DFG0004A



PACKAGE OUTLINE

SOIC - 2.4 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



4227022/C 07/2024

NOTES:

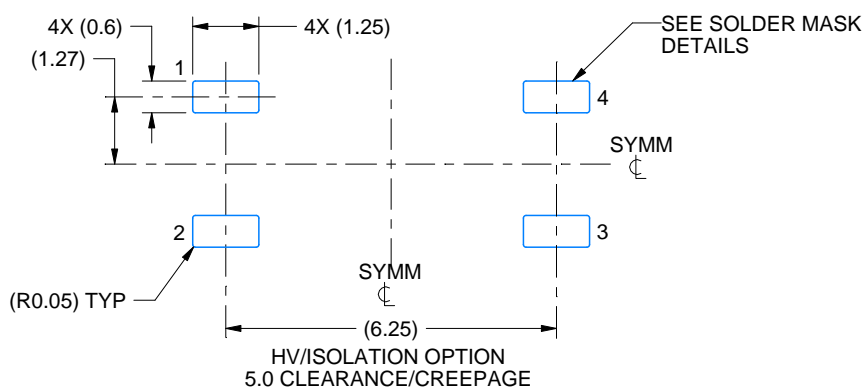
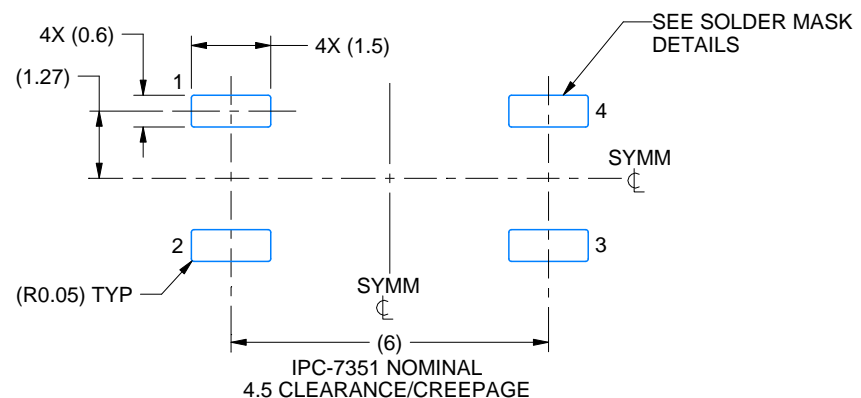
1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
4. This dimension does not include interlead flash.

EXAMPLE BOARD LAYOUT

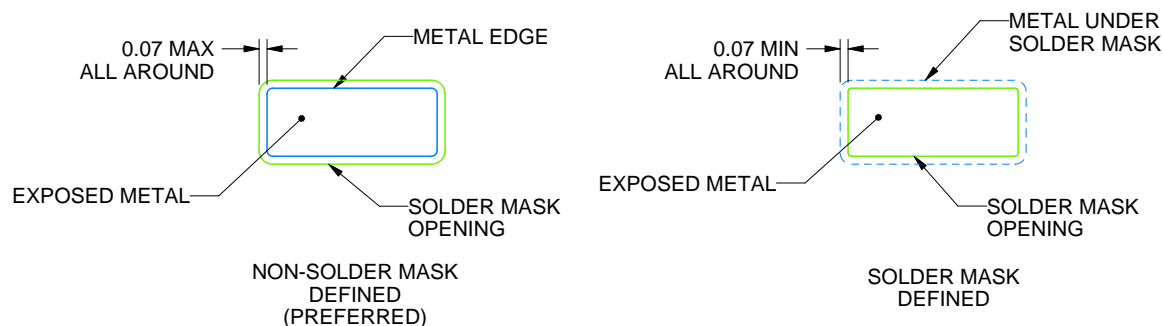
DFG0004A

SOIC - 2.4 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE: 7X



SOLDER MASK DETAILS

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NOTES: (continued)

5. Publication IPC-7351 may have alternate designs.

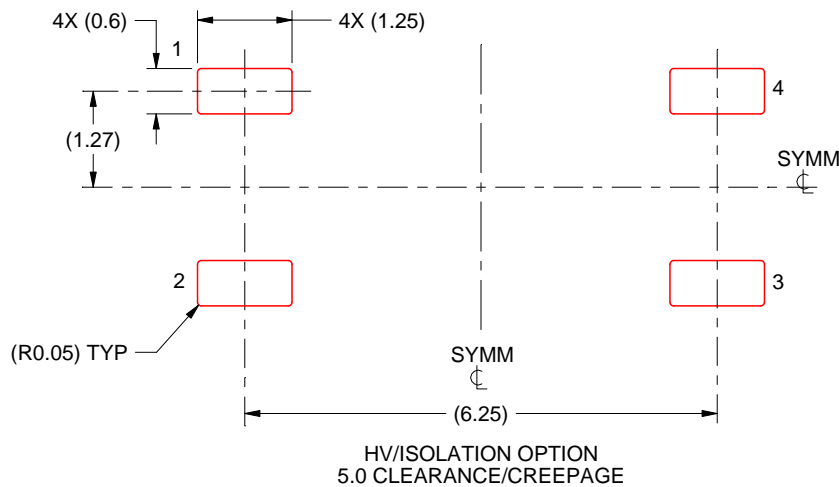
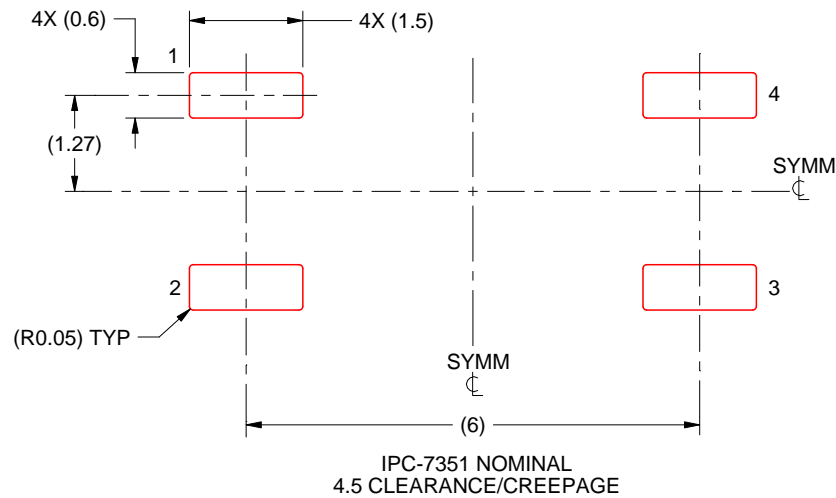
6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

EXAMPLE STENCIL DESIGN

DFG0004A

SOIC - 2.4 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL
SCALE: 10X

4227022/C 07/2024

NOTES: (continued)

7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
8. Board assembly site may have different recommendations for stencil design.

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